



TEST REPORT

REPORT NUMBER: I21W00004-EMC

ON

Type of Equipment: Tracker

Type of Designation: AT Pro NG

Manufacturer: Micron Electronics LLC.

ACCORDING TO Subpart B, PART 15, RADIO FREQUENCY DEVICES

Chongqing Academy of Information and Communication Technology

Month date, year Apr, 08, 2021

Signature

面罗勇

Xiang Luoyong

Director

Note:

The test results in this test report relate only to the devices specified in this report. This report shall not be reproduced except in full without the written approval of Chongqing Academy of Information and Communication Technology.





Revision Version

Report Number	Revision	Date	Memo
I21W00004-EMC	00	2021-04-08	Initial creation of test report





FCC ID: ZKQ-ATPNG

Report Date: 2021-04-08

Test Firm Name: Chongqing Academy of Information and Communication

Technology

FCC Registration Number: CN1239

Statement

The measurements shown in this report were made in accordance with the procedures described on test pages. All reported tests were carried out on a sample equipment to demonstrate limited compliance with FCC CFR 47 Part 15B. The sample tested was found to comply with the requirements defined in the applied rules.





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1 General Information

1.1 Notes

All reported tests were carried out on a sample equipment to demonstrate limited compliance with FCC CFR 47 Part15B.

The test results of this test report relate exclusively to the item(s) tested as specified in section 2.

The following deviation from, additions to, or exclusions from the test specifications have been made. See Annex C.

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1.2 Testers

Name: Chen Xin

Position: Engineer

Department: Department of EMC test

Date: 2021-04-08

Signature:

Editor of this test report:

Name: Xiao Yu

Position: Engineer

Department: Department of EMC test

Date: 2021-04-08

Signature:

Technical responsibility for area of testing:

Name: Xiang Luoyong

Position: Manager

Department: Department of EMC test

Date: 2021-04-08

Signature:





1.3 Testing Laboratory information

1.3.1 Location				
Name:	Chongqing Academy of Information and Communcations			
Address:	Building B, Technology Innovation Center, No.8, Yuma			
	Road, Chayuan New Area, Nan'an District, Chongqing,			
	People's Republic of China, 401336			
Tel:	+86 23 88069965			
Fax:	+86 23 88608777			
Email:	liqiao@caict.ac.cn			
1.3.2 Details of accreditation s	status			
Accredited by:				
Registration number:				
Standard:				
1.3.3 Test location, where diffe	erent from section 1.3.1			
Name:				
Address:				





1.4 Details of applicant or manufacturer

1.4.1 Applicant

Name: Micron Electronics LLC.

Address: 1001 Yamato Road, Suite 400, Boca Raton, FL 33431, USA

Country: USA

Telephone: 1 888 538 3489

Fax: --

Contact: Ping Cheng

Email: pcheng@micron-electronics.com

1.4.2 Manufacturer (if different from applicant in section 1.4.1)

Name: Micron Electronics LLC.

Address: 1001 Yamato Road, Suite 400, Boca Raton, FL 33431, USA

Country: USA





2 Test Item

2.1 General Information

Manufacturer: Micron Electronics LLC.

Name: Tracker
Model Number: AT Pro NG

Serial Number: K4L10504010013 IMEI: 866884045634250

Production Status: Product
Receipt date of test item: 2021-03-22

2.2 Outline of EUT

The EUT AT Pro NG is a Product supporting CAT M1 Band 2/4/5/12/13, GSM850 and PCS1900.

2.3 Modifications Incorporated in EUT

The EUT has not been modified from what is described by the brand name and unique type identification stated above.

2.4 Equipment Configuration

Equipment configuration list:

Item	Generic Description	Manufacturer	Туре	Serial No.	Remarks
A	Product	Micron Electronics LLC.	AT Pro NG	K4L1050401 0013	None

2.5 Other Information

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3 Summary of Test Results

A brief summary of the tests carried out is shown as following.

Configuration1		
Specification Clause	Name of Test	Result
15.107	Conducted limits	P
15.109	Radiated Emission limits	P

4.Test equipment and Test software

Test equip	Test equipment Used:							
Number	Description	Manufact urer	Model Number	Serial Number	Cal Due	State		
1	EMI Test Receiver	R/S	ESU	100367	2021-06-25	Normal		
2	Ultra Broadband Antenna	R/S	VULB 9163	00995	2023-04-03	Normal		
3	Double-Ridged Horn Antenna	R/S	HF907	100357	2021-08-20	Normal		
4	Fully-Anechoic Chamber	ETS	11.8m×6.5m×6. 3m	CT000174- 1035	2024-01-22	Normal		
5	AMN	R/S	ENV216	101128	2021-06-25	Normal		
6	EMI Test Receiver	R/S	ESCI 9KHz- 3GHZ	101214	2021-06-25	Normal		

Test softwa	Test software Used:							
Number	Test item	Test software name	Manufacturer	Version:				
1	Radiated Emission	EMC32	R/S	V8.51.0				
2	Conducted Emission	EMC32	R/S	V8.51.0				





5 Test Results

5.1 Radiated Emission

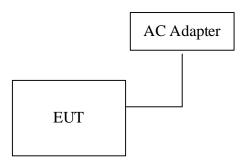
Specifications:	15.109			
Date of Tests	2021-03-22-2021-04-08			
Test conditions:	Ambient Temperature:15°C-35°C			
	Relative Humidity:30%-60%			
	Air pressure: 86-106kPa			
Operation Mode	Normal			
Test Results:	Pass			

Limit Level Construction(Except for Class A digital devices):

	8
Frequency Range (MHz)	Quasi-Peak (dBuV/m)
30-88	40
88-216	43.5
216-960	46
Above 960	54

Frequency Range (MHz)	Peak (dBuV/m)	Average (dBuV/m)
Above 1000	74	54

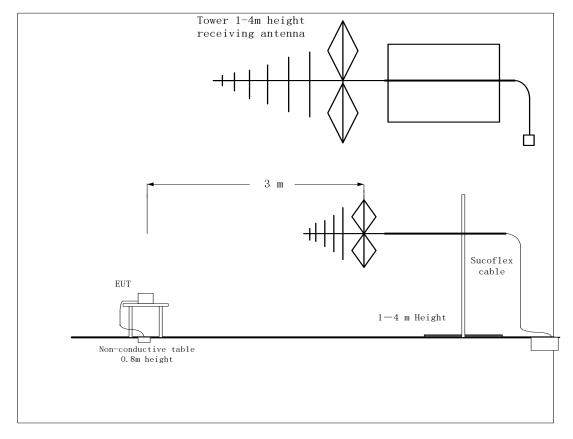
EUT Setup:







Test Setup:



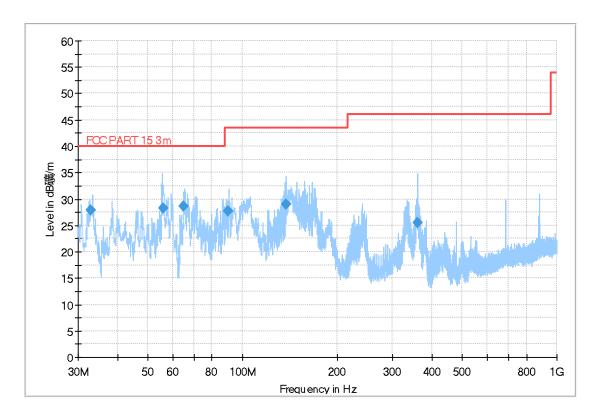
Test Method:

For 30-1000MHz, the EUT was placed on the top of a rotating 0.8m table above the ground at a semi-anechoic chamber. The distance between the EUT and the received antenna was 3 meters. The table was rotated 360 degree and the received antenna mounted on a variable-height antenna tower was varied from 1m to 4m to find the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna were set during the measurement. Tested in accordance with the procedures of ANSI C63.4-2014, section 8.3.

For 1000-18000MHz, the maximal emission value was acquired by adjusting the antenna height, and the table was rotated 360 degree to determine the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna were set during the measurement.



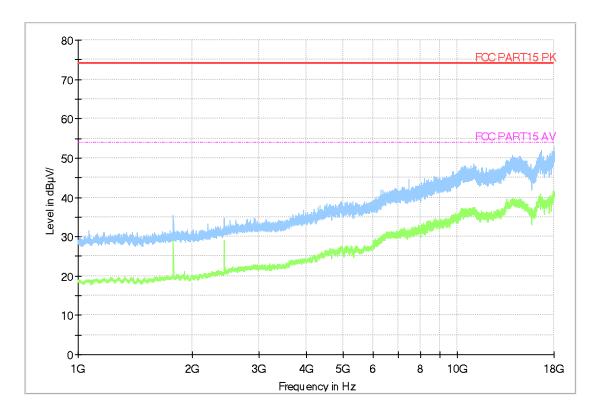
Test Data



RE 30M-1G

Frequency	QuasiPeak	Limit	Margin	Meas.	Bandwidth	Height	Pol	Azimuth	Corr.
(MHz)	(dB 礦/m)	(dB 礦/m)	(dB)	Time	(kHz)	(cm)		(deg)	(dB)
32.946500	27.85	40.00	12.15	1000.0	120.000	120.0	V	17.0	-22.1
55.822500	28.20	40.00	11.80	1000.0	120.000	116.0	V	-41.0	-18.4
64.874000	28.54	40.00	11.46	1000.0	120.000	105.0	V	-38.0	-21.2
90.191000	27.76	43.50	15.74	1000.0	120.000	105.0	V	-11.0	-22.6
137.793500	28.98	43.50	14.52	1000.0	120.000	100.0	V	45.0	-24.3
359.994000	25.51	46.00	20.49	1000.0	120.000	150.0	V	-16.0	-17.2





RE 1-18G





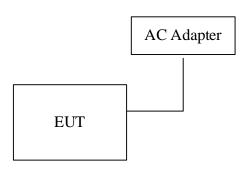
5.2 Conducted Emission

Specifications:	15.107			
Date of Tests	2021-03-22-2021-04-08			
Test conditions:	Ambient Temperature:15°C-35°C			
	Relative Humidity:30%-60%			
	Air pressure: 86-106kPa			
Operation Mode	Normal			
Test Results:	Pass			

Limit Level Construction:

Frequency Range (MHz)	Conducted Limit (dBuV)				
	Quasi-peak	Average			
0.15-0.5	66 to 56*	56 to 46*			
0.5-5	56	46			
5-30	60	50			
*Decreases with the logarithm of the	frequency				

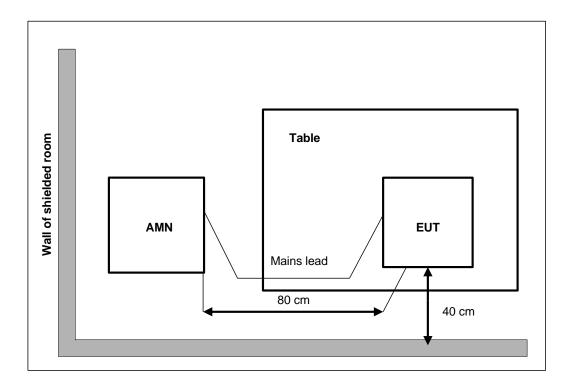
EUT Setup:







Test Setup:



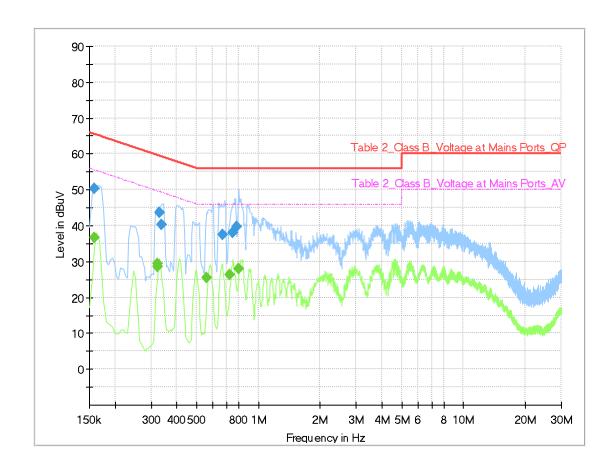
Test Method:

For equipment that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency or frequencies with the band 150 kHz to 30MHz shall not exceed the limits. Both lines of the power mains connected to the EUT were checked for maximum conducted interference. Tested in accordance with the procedures of ANSI C63.4-2014, section 7.3



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L&N 150KHz-30MHz

Frequency	QuasiPeak	CAverage	Limit	Margin	Meas. Time	Line	Filter	Corr.
0.159000	50.37		65.52	15.14	1000.0	N	ON	10.2
0.159000		36.60	55.52	18.92	1000.0	L1	ON	10.2
0.320978		29.30	49.68	20.38	1000.0	L1	ON	9.9
0.323382		28.63	49.62	20.98	1000.0	L1	ON	9.9
0.329757	43.53		59.46	15.93	1000.0	L1	ON	9.9
0.337103	40.19		59.27	19.09	1000.0	L1	ON	9.9
0.557691		25.36	46.00	20.64	1000.0	L1	ON	10.0
0.669750	37.52		56.00	18.48	1000.0	L1	ON	10.0
0.726596		26.31	46.00	19.69	1000.0	N	ON	10.0
0.753044	38.10		56.00	17.90	1000.0	L1	ON	9.9
0.781566	39.64		56.00	16.36	1000.0	L1	ON	9.9
0.803735		27.89	46.00	18.11	1000.0	N	ON	9.9

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Test photo

See the Pic1~3 in document" I21W00004 EMC Test Setup Photos".

Annex A External Photos

See the document" I21W00004 -External Photos".

Annex B Internal Photos

See the document" I21W00004 -Internal Photos".

ANNEX C Deviations from Prescribed Test Methods

No deviation from Prescribed Test Methods.

